SCOPE:

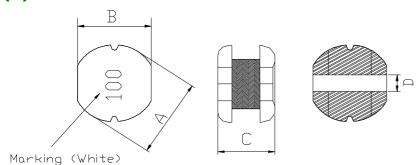
This specification applies to the Pb Free high current type SMD inductors for MSCD-108-SERIES

PRODUCT INDENTIFICATION

MSCD - 108 - 100 M

- 1 2 3 4
- **1** Product Code
- **2 Dimensions Code**
- **3 Inductance Code**
- **4** Tolerance Code

(1) SHAPES AND DIMENSIONS



A: 10.0± 0.3 mm

B: 9.0± 0.3 mm

C: 8.50 Max. mm

D: 3.20 Typ. mm

(2) ELECTRICAL SPECIFICATIONS SEE TABLE 1

TEST INSTRUMENTS

L: HP 4284A PRECISION LCR METER (or equivalent)

RDC: CHROMA MODEL 16502 MILLIOHMMETER (or equivalent)

(3) CHARACTERISTICS

- (3)-1 Ambient temperature +60°C Max.
- (3)-2 Operate temperature range -40° C $\sim +125^{\circ}$ C (Including self temp. rise)
- (3)-3 Storage temperature range -40° C $\sim +125^{\circ}$ C



TABLE 1

MAGLAYERS	Inductance	Percent	Test	Resistance	Rated DC Current	Manking
PT/NO.	L(µH)	Tolerance	Frequency	RDC(Ω) Max.	IDC(A)	Marking
MSCD-108-6R8	6.8	M,N	100kHz/0.25V	33.7m	4.30	6R8
MSCD-108-100	10	M,N	100kHz/0.25V	36m	4.05	100
MSCD-108-120□	12	M,N	100kHz/0.25V	38m	3.60	120
MSCD-108-150□	15	M,N	100kHz/0.25V	40m	3.34	150
MSCD-108-180□	18	M,N	100kHz/0.25V	50m	3.05	180
MSCD-108-220□	22	M,N	100kHz/0.25V	60m	2.80	220
MSCD-108-270□	27	M,N	100kHz/0.25V	70m	2.50	270
MSCD-108-330□	33	M,N	100kHz/0.25V	80m	2.40	330
MSCD-108-390□	39	M,N	100kHz/0.25V	90m	2.22	390
MSCD-108-470□	47	M,N	100kHz/0.25V	0.11	2.00	470
MSCD-108-560□	56	M,N	100kHz/0.25V	0.12	1.90	560
MSCD-108-680□	68	M,N	100kHz/0.25V	0.15	1.80	680
MSCD-108-820□	82	M,N	100kHz/0.25V	0.19	1.60	820
MSCD-108-101□	100	K,M	100kHz/0.25V	0.23	1.50	101
MSCD-108-121□	120	K,M	100kHz/0.25V	0.32	1.40	121
MSCD-108-151□	150	K,M	100kHz/0.25V	0.37	1.30	151
MSCD-108-181□	180	K,M	100kHz/0.25V	0.42	1.20	181
MSCD-108-221□	220	K,M	100kHz/0.25V	0.44	1.00	221
MSCD-108-271□	270	K,M	100kHz/0.25V	0.55	0.95	271
MSCD-108-331□	330	K,M	100kHz/0.25V	0.60	0.90	331
MSCD-108-391□	390	K,M	100kHz/0.25V	0.67	0.80	391
MSCD-108-471□	470	K,M	100kHz/0.25V	0.88	0.70	471
MSCD-108-561□	560	K,M	100kHz/0.25V	1.04	0.65	561
MSCD-108-681□	680	K,M	100kHz/0.25V	1.18	0.60	681
MSCD-108-821□	820	K,M	100kHz/0.25V	1.38	0.50	821
MSCD-108-102	1000	K,M	100kHz/0.25V	1.74	0.48	102

[※] ☐ specify the inductance tolerance,K(±10%),M(±20%),N(±30%)



[%]IDC : Based on inductance change (\triangle L/Lo : drop 10% Max.) @ ambient temp. 25°C and temperature rise (\triangle T : 40°C TYP.)

(4) RELIABILITY TEST METHOD

MECHANICAL

TEST ITEM	SPECIFICATION	TEST DETAILS			
Substrate bending	∆L/Lo≦±5%	The sample shall be soldered onto the printed circuit board			
		in figure 1 and a load applied unitil the figure in the arrow			
	There shall be	direction is made approximately 3mm.(keep time 30 seconds)			
	no mechanical	PCB dimension shall the page 7/9			
	damage or elec-	F(Pressurization)			
	trical damege.	Л			
		R5 45±2 45±2 10 20 R340			
		PRESSURE ROD figure-1			
Vibration	∆L/Lo≦±5%	The sample shall be soldered onto the printed circuit board			
		and when a vibration having an amplitude of 1.52mm			
	There shall be	and a frequency of from 10 to 55Hz/1 minute repeated should			
	no mechanical	be applied to the 3 directions (X,Y,Z) for 2 hours each.			
	damage.	(A total of 6 hours)			
Caldanahilita	New solder	Flux (rosin, isopropyl alcohol{JIS-K-1522}) shall be coated			
Solderability	More than 90%	over the whole of the sample before hard, the sample shall			
		then be preheated for about 2 minutes in a temperature of			
		130∼150℃ and after it has been immersed to a depth 0.5mm			
		below for 3±0.2 seconds fully in molten solder M705 with			
		a temperature of 245±5℃.			
		More than 90% of the electrode sections shall be couered			
		with new solder smoothly when the sample is taken out of			
		the solder bath.			

MECHANICAL

TEST ITEM	SPECIFICATION						
TEST ITEM Resistance to Soldering heat (reflow soldering)	There shall be no damage or problems.	Temperature profile of reflow soldering soldering (Peak temperature 260±3°C 10 sec 250 Pre-heating 150 150 2 min 10 sec. 2 min or more The specimen shall be passed through the reflow oven with the condition shown in the above profile for 1 time.					
		The specimen shall be stored at standard atmospheric conditions for 1 hour, after which the measurement shall be made.					

ELECTRICAL

TEST ITEM	SPECIFICATION	TEST DETAILS		
Insulation	There shall be	DC 100V voltage shall be applied across this sample of top		
resistance	no other	surface and the terminal.		
	damage or	The insulation resistance shall be more than 1 \times 10 ⁸ Ω .		
	problems.			
Dielectric	There shall be	AC 100V voltage shall be applied for 1 minute acrosset the top		
withstand	no other	surface and the terminal of this sample		
voltage	damage or			
	problems.			
Temperature	∆L/L20°C ≦±10%	The test shall be performed after the sample has stabilized in		
characteristics	0~2000 ppm/℃	an ambient temperature of -20 to +85°C ,and the value		
		calculated based on the value applicable in a normal		
		temperature and narmal humidity shall be △L/L20°C ≦±10%.		



ENVIROMENT CHARACTERISTICS

TEST ITEM				SPECIFICATION				
High temperature	∆L/Lo≦±5%	The samp	The sample shall be left for 96±4 hours in an atmospere with					
storage		a tempera	a temperature of 85±2℃ and a normal humidity.					
	There shall be	Upon con	Upon completion of the measurement shall be made after the					
	no mechanical	sample ha	sample has been left in a normal temperature and normal					
	damage.	humidity 1	humidity for 1 hour.					
Low temperature	∆L/Lo≦±5%	The samp	le s	hall be left for 96±4 hoเ	ırs in an atmosphere	with		
storage		a tempera	a temperature of -25±3℃.					
	There shall be	Upon con	Upon completion of the test, the measurement shall be made					
	no mechanical	after the s	amp	ole has been left in a no	ormal temperature an	d		
	damage.	normal humidity for 1 hour.						
Change of	∆L/Lo≦±5%	The samp	The sample shall be subject to 5 continuos cycles, such as shown					
temperature		in the tab	in the table 2 below and then it shall be subjected to standard					
	There shall be	atmosphe	eric (conditions for 1 hour, a	fter which measuren	nent		
	no other dama-	shall be m	nade	·.				
	ge of problems							
				table 2		=		
				Temperature	Duration			
			1	−25±3 °C	30 min.			
				(Themostat No.1)				
			2	Standard	No.1→No.2			
				atmospheric				
			3	85±2 ℃	30 min.			
				(Themostat No.2)				
			4	Standard	No.2→No.1			
				atmospheric				
Moisture storage	∆L/Lo≦±5%	The samp	le s	hall be left for 96±4 hou	ırs in a temperature o	of		
	40±2℃ and a humidity(RH) of 90∼95%.							
	There shall be upon completion of the test, the measurement shall be after the sample has been left in a normal temperature and damage.					nade		
Test conditions :	1	1						

The sample shall be reflow soldered onto the printed circuit board in every test.



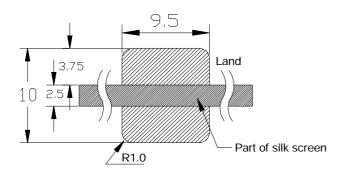
(5) LAND DIMENSION (Ref.)

PCB: GLASS EPOXY t=1.6mm

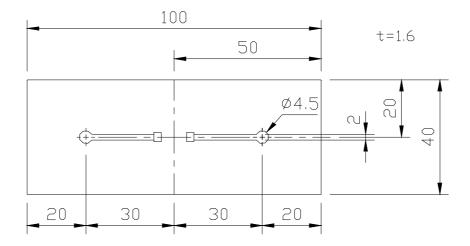
(5)-1 LAND PATTERN DIMENSIONS

(STANDARD PATTERN)

Unit:mm



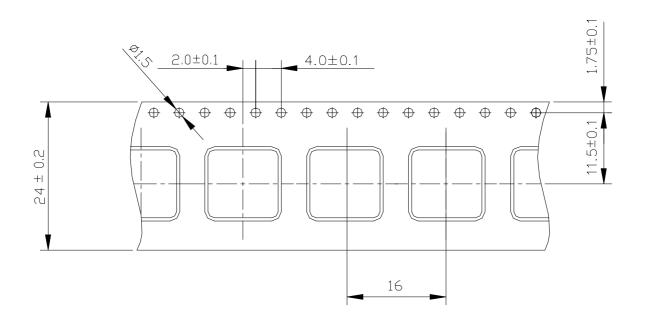
(5)-2 SUBSTRATE BENDING TEST BENDING TEST BOARD



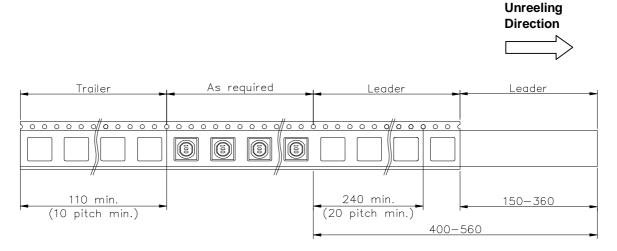


(6) PACKAGING

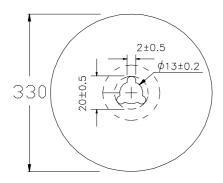
(6)-1 CARRIER TAPE DIMENSIONS (mm)

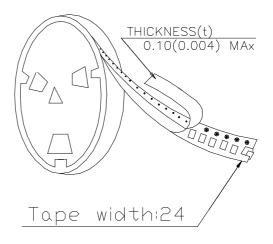


(6)-2 TAPING DIMENSIONS (mm)



(6)-3 REEL DIMENSIONS (mm)





(6)-4 QUANTITY

500pcs/Reel

The products are packaged so that no damage will be sustained.

